


<b>Search Notes</b>  	<b>Application/Control No.</b>  10576055	<b>Applicant(s)/Patent Under Reexamination</b>  TANAKA ET AL.
	<b>Examiner</b>  DAVID YI	<b>Art Unit</b>  4173

SEARCHED			
Class	Subclass	Date	Examiner
709	201	1/27/09	D.Y.

SEARCH NOTES		
Search Notes	Date	Examiner
see patent family publication documents	1/27/09	D.Y.
consulted w/ Yemane Mesfin on PCT info	1/27/09	D.Y.
see attached EAST search history	1/27/09	D.Y.

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/D. Y./ Examiner.Art Unit 4173	
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